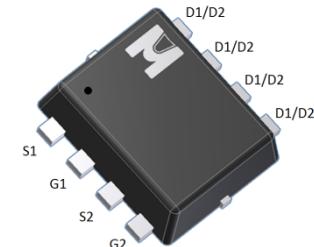
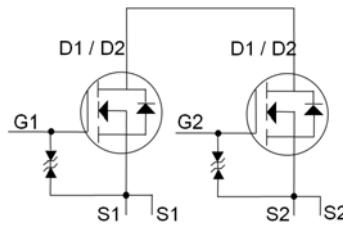


**Dual N-Channel Logic Level Enhancement Mode Field Effect Transistor**

**Product Summary:**

BV <sub>DSS</sub>	20V
R <sub>DSON</sub> (MAX.)	14mΩ
I <sub>D</sub>	9.5A



Pb-Free Lead Plating & Halogen Free

ESD Protection



**ABSOLUTE MAXIMUM RATINGS (T<sub>A</sub> = 25 °C Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNIT
Gate-Source Voltage		V <sub>GS</sub>	±12	V
Continuous Drain Current	T <sub>A</sub> = 25 °C	I <sub>D</sub>	9.5	A
	T <sub>A</sub> = 70 °C		7.7	
Pulsed Drain Current <sup>1</sup>		I <sub>DM</sub>	40	
Power Dissipation	T <sub>A</sub> = 25 °C	P <sub>D</sub>	2.1	W
	T <sub>A</sub> = 70 °C		1.3	
Operating Junction & Storage Temperature Range		T <sub>j</sub> , T <sub>stg</sub>	-55 to 150	°C

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNIT
Junction-to-Ambient <sup>3</sup> (t ≤ 10s)	R <sub>θJA</sub>	60	105	°C / W
Junction-to-Ambient <sup>3</sup>	R <sub>θJA</sub>			

<sup>1</sup>Pulse width limited by maximum junction temperature.

<sup>2</sup>Duty cycle ≤ 1%

<sup>3</sup>The value of R<sub>θJA</sub> is measured with the device mounted on a 1 in<sup>2</sup> pad of 2 oz copper.

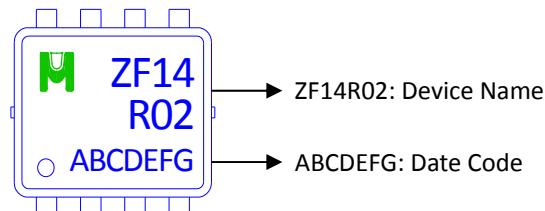
ELECTRICAL CHARACTERISTICS ( $T_J = 25^\circ\text{C}$ , Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{GS} = 0V, I_D = 250\mu\text{A}$	20			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	0.35	0.65	1.0	
Gate-Body Leakage	$I_{GSS}$	$V_{DS} = 0V, V_{GS} = \pm 12V$			$\pm 10$	$\mu\text{A}$
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 16V, V_{GS} = 0V$			1	$\mu\text{A}$
		$V_{DS} = 16V, V_{GS} = 0V, T_J = 125^\circ\text{C}$			10	
On-State Drain Current <sup>1</sup>	$I_{D(\text{ON})}$	$V_{DS} = 5V, V_{GS} = 4.5V$	9.5			A
Drain-Source On-State Resistance <sup>1</sup>	$R_{DS(\text{ON})}$	$V_{GS} = 4.5V, I_D = 5A$		12.5	14	$\text{m}\Omega$
		$V_{GS} = 2.5V, I_D = 4A$		14	17	
		$V_{GS} = 1.8V, I_D = 3A$		16	25	
Forward Transconductance <sup>1</sup>	$g_f$	$V_{DS} = 5V, I_D = 5A$		14		S
DYNAMIC						
Input Capacitance	$C_{iss}$	$V_{GS} = 0V, V_{DS} = 10V, f = 1\text{MHz}$		987		$\text{pF}$
Output Capacitance	$C_{oss}$			139		
Reverse Transfer Capacitance	$C_{rss}$			124		
Gate Resistance	$R_g$	$V_{GS} = 15\text{mV}, V_{DS} = 0V, f = 1\text{MHz}$		2.2		$\Omega$
Total Gate Charge <sup>1,2</sup>	$Q_g$	$V_{DS} = 10V, V_{GS} = 4.5V, I_D = 5A$		15.1		$\text{nC}$
Gate-Source Charge <sup>1,2</sup>	$Q_{gs}$			1.1		
Gate-Drain Charge <sup>1,2</sup>	$Q_{gd}$			4.2		
Turn-On Delay Time <sup>1,2</sup>	$t_{d(on)}$	$V_{DS} = 10V, I_D = 1A, V_{GS} = 4.5V, R_{GS} = 6\Omega$		10		$\text{nS}$
Rise Time <sup>1,2</sup>	$t_r$			15		
Turn-Off Delay Time <sup>1,2</sup>	$t_{d(off)}$			40		
Fall Time <sup>1,2</sup>	$t_f$			18		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ( $T_C = 25^\circ\text{C}$ )						
Continuous Current	$I_S$				2	A
Pulsed Current <sup>3</sup>	$I_{SM}$				8	
Forward Voltage <sup>1</sup>	$V_{SD}$	$I_F = 6A, V_{GS} = 0V$		0.78	1.1	V

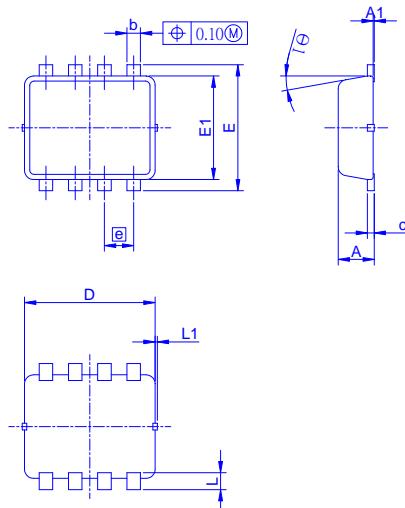
<sup>1</sup>Pulse test : Pulse Width  $\leq 300 \mu\text{sec}$ , Duty Cycle  $\leq 2\%$ .<sup>2</sup>Independent of operating temperature.<sup>3</sup>Pulse width limited by maximum junction temperature.

### Ordering & Marking Information:

Device Name: EMZF14R02W for DFN 3 x 3



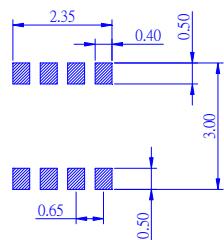
### Outline Drawing



Dimension in mm

Dimension	A	A1	b	c	D	E	E1	e	L	L1	θ1
Min.	0.70	0	0.24	0.08					0.20	0	0°
Typ.	0.80		0.30	0.152	2.90	2.80	2.30	0.65	0.375		10°
Max.	0.90	0.05	0.35	0.25					0.45	0.10	12°

### Recommended minimum pads



## TYPICAL CHARACTERISTICS

